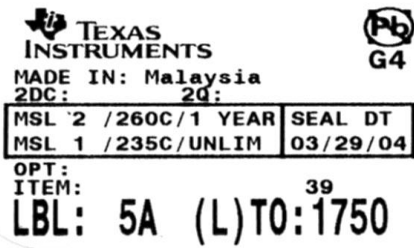


PCN Number:	20200305000.1		PCN Date:	Mar 10, 2020																			
Title:	Qualification of RFAB as an additional Wafer Fab Site option for select devices in HPA07 Technology																						
Customer Contact:	PCN Manager		Dept:	Quality Services																			
Proposed 1st Ship Date:	Jun 10, 2020		Estimated Sample Availability:	Date provided at sample request.																			
Change Type:																							
☐	Assembly Site	☐	Assembly Process	☐	Assembly Materials																		
☐	Design	☐	Electrical Specification	☐	Mechanical Specification																		
☐	Test Site	☐	Packing/Shipping/Labeling	☐	Test Process																		
☐	Wafer Bump Site	☐	Wafer Bump Material	☐	Wafer Bump Process																		
☒	Wafer Fab Site	☒	Wafer Fab Materials	☐	Wafer Fab Process																		
	☐	Part number change																					
PCN Details																							
Description of Change:																							
Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.																							
<table border="1"> <thead> <tr> <th colspan="3">Current Sites</th> <th colspan="3">Additional Sites</th> </tr> <tr> <th>Current Fab Site</th> <th>Process</th> <th>Wafer Diameter</th> <th>Additional Fab Site</th> <th>Process</th> <th>Wafer Diameter</th> </tr> </thead> <tbody> <tr> <td>AIZU</td> <td>HPA07</td> <td>200mm</td> <td>RFAB</td> <td>HPA07</td> <td>300mm</td> </tr> </tbody> </table>						Current Sites			Additional Sites			Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	AIZU	HPA07	200mm	RFAB	HPA07	300mm
Current Sites			Additional Sites																				
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter																		
AIZU	HPA07	200mm	RFAB	HPA07	300mm																		
Qual details are provided in the Qual Data Section.																							
Reason for Change:																							
Continuity of Supply																							
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):																							
None																							
Changes to product identification resulting from this PCN:																							
Current																							
Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City																				
AIZU	CU2	JPN	Aizuwakamatsu-shi																				
New Fab Site																							
Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City																				
RFAB	RFB	USA	Richardson																				
Sample product shipping label (not actual product label)																							
  <div style="float: right;"> <p>(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (Y) 0033317 (20L) CS0: SHE (21L) CC0: USA (22L) AS0: MLA (23L) AC0: MYS</p> </div>																							
Product Affected Group:																							
AMC7834IRTQR	AMC7834IRTQT	SNE551EIRHBR																					

Qualification Report

Approve Date 11-October-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: AMC7834IRTQR	QBS Device: AMC7836IPAP	QBS Process Reference: CD3232A1YFFR
AC	Autoclave, 121C/2 atm	96 Hours	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	3/3000/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0
HBM	ESD - HBM	1000 V	1/3/0	-	3/9/0
CDM	ESD - CDM	1000 V	1/3/0	-	3/9/0
HTOL	Life Test, 150C	300 Hours	-	1/77/0	-
HTOL	Life Test, 140C	480 Hours	-	-	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0
LU	Latch-up	(per JESD78)	1/6/0	-	3/18/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	3/231/0

- QBS: Qual By Similarity

- Qual Device AMC7834IRTQR is qualified at LEVEL3-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 03-March-2020

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: SNE551EIRHBR	QBS Process Reference: ADS8028IRTJR	QBS Process Reference: CD3232A1YFFR	QBS Package Reference: SH6966ACC0RGCRG4
AC	Autoclave, 121C/2 atm	96 Hours	-	-	-	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	3/3000/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	3/231/0
HBM	ESD - HBM	2500 V	1/3/0	1/3/0	3/9/0	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	3/9/0	-
HTOL	Life Test, 150C	300 Hours	-	3/231/0	-	-
HTOL	Life Test, 140C	480 Hours	-	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0	3/231/0
LU	Latch-up	(per JESD78)	1/6/0	1/6/0	3/18/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-

- QBS: Qual By Similarity

- Qual Device SNE551EIRHBR is qualified at LEVEL3-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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PCN# 20200305000.1

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